

Search Notes

Application/Control No.

10/600,014

Examiner

Shew-Fen Lin

Applicant(s)/Patent under Reexamination

CHATTERJEE ET AL.

Art Unit

2166

SEARCHED

Class	Subclass	Date	Examiner
715	512	10/12/2006	SFL
715	730	10/12/2006	SFL
707	100	10/12/2006	SFL
709	200-250	10/12/2006	SFL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Google	10/12/2006	SFL
East (US-PUB, USPAT, USOCR, EPO, JPO, IBM-TDB	10/12/2006	SFL

INTERFERENCE SEARCHED

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